



# RF Transistors

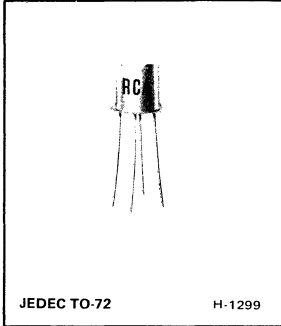
## 2N6389

### UHF/MATV Low-Noise Silicon N-P-N Transistor

For High-Gain Small-Signal Applications in UHF TV  
RF Amplifiers and UHF MATV Amplifiers

#### Features:

- Low noise figure:
  - NF = 3 dB (typ.) at 450 MHz, 1.5 mA
  - = 4 dB (typ.) at 890 MHz, 1.5 mA
  - = 6 dB (typ.) at 890 MHz, 10 mA
- High gain (tuned, unneutralized):
  - $G_{PE} = 15$  dB (min.) at 890 MHz



RCA 2N6389<sup>●</sup> is an epitaxial silicon n-p-n planar transistor intended for low-power, small-signal applications where both low noise and high gain are desirable. It utilizes a hermetically sealed four-lead JEDEC TO-72 package. All of the elements of the transistor are insulated from the case, which may be grounded by means of the fourth lead.

- High gain-bandwidth product
- Large dynamic range
- Low distortion
- Low collector-base capacitance

● Formerly RCA No. 40989.

#### MAXIMUM RATINGS, Absolute-Maximum Values:

*COLLECTOR-TO-BASE VOLTAGE .....	$V_{CBO}$	20	V
*COLLECTOR-TO-EMITTER VOLTAGE .....	$V_{CEO}$	12	V
*EMITTER-TO-BASE VOLTAGE .....	$V_{EBO}$	2.5	V
*COLLECTOR CURRENT (Continuous) .....	$I_C$	40	mA
*TRANSISTOR DISSIPATION:	$P_T$		
At ambient temperatures up			
to 25°C .....		200	mW
At ambient temperatures above			
25°C .....			Derate linearly
*TEMPERATURE RANGE:			at 1.14 mW/°C
Storage and Operating			
(Junction) .....			-65 to +200° C
*LEAD TEMPERATURE (During soldering):			
At distances $\geq 1/16$ in. (1.59 mm) from			
seating plane for 60 s max. ....			300° C

\*In accordance with JEDEC registration data format  
JS-9 RDF-1.

ELECTRICAL CHARACTERISTICS, At Ambient Temperature ( $T_A$ ) = 25°C

CHARACTERISTIC	SYMBOL	TEST CONDITIONS					LIMITS		UNITS
		VOLTAGE V dc		CURRENT mA dc			MIN.	MAX.	
		$V_{CB}$	$V_{CE}$	$I_E$	$I_B$	$I_C$			

## STATIC

* Collector Cutoff Current	$I_{CBO}$	15		0			—	20	nA
* Emitter Cutoff Current	$I_{EBO}$	$(V_{EB})_1$				0	—	1	$\mu$ A
* Collector-to-Base Breakdown Voltage	$V_{(BR)CBO}$			0		0.001	20	—	V
* Collector-to-Emitter Breakdown Voltage	$V_{(BR)CEO}$				0	3	12	—	V
* Emitter-to-Base Breakdown Voltage	$V_{(BR)EBO}$			0.01		0	2.5	—	V
* DC Forward Current Transfer Ratio	$h_{FE}$		1			3	25	250	
Thermal Resistance: (Junction-to-Case)	$R_{\theta JC}$						—	880	$^{\circ}$ C/W

## DYNAMIC

Device Noise Figure: f = 890 MHz = 890 MHz = 450 MHz	NF	10 10 10				1.5 10 1.5	— — —	4(typ.) 6(typ.) 3(typ.)	dB
Small-Signal Common-Base Power Gain (f = 890 MHz)	$G_{PB}$	10				10	15	—	dB
* Small-Signal, Short Circuit Forward Current Transfer Ratio (f = 1 kHz)	$h_{fe}$		1			3	25	250	
* Magnitude of Small-Signal Short Circuit Forward Current Transfer Ratio (f = 200 MHz)	$ h_{fe} $		10			1.5	5	15	
* Collector-to-Base Time Constant (f = 31.9 MHz)	$r_b' C_c$	10		1.5			1	15	ps
* Collector-to-Base Capacitance (f = 1 MHz)	$C_{cb}$	10		0			0.4	0.55	pF

\* In accordance with JEDEC registration data format JS-9 RDF-1.

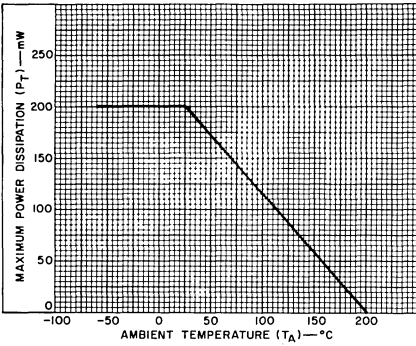


Fig. 1 - Power dissipation vs. ambient temperature.

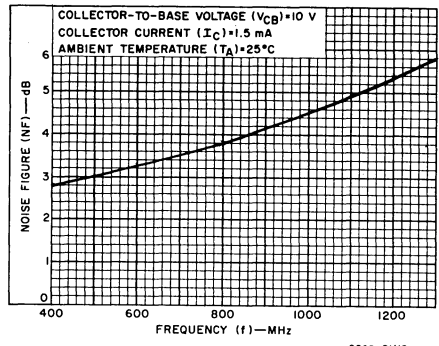


Fig. 2 - Typical common-base noise figure vs. frequency.

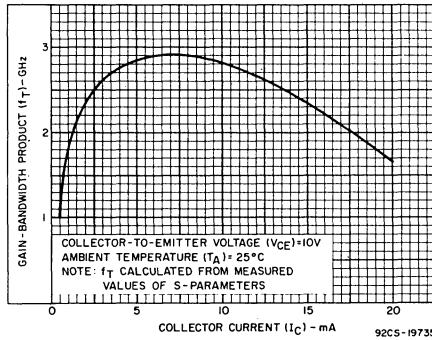
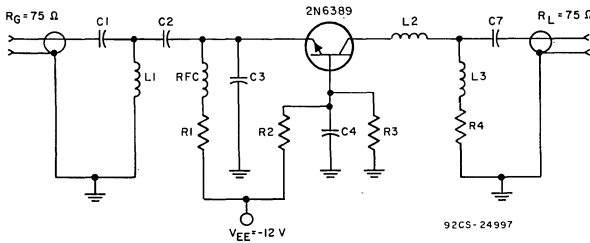


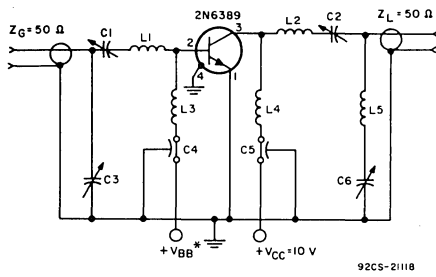
Fig. 3 - Gain-bandwidth product vs. collector current.



- C<sub>1</sub>, C<sub>7</sub>: 3.3 pF disc ceramic
- C<sub>2</sub>: 2.7 pF disc ceramic
- C<sub>3</sub>: 1 pF disc ceramic
- C<sub>4</sub>: 25 pF, ATC-100 or equivalent

- L<sub>1</sub>, L<sub>2</sub>: 2 turns, No. 18 wire, 0.125 in. (3.175 mm) ID
- RFC: 8 turns No. 28 wire, 0.062 in. (1.57 mm) ID
- R<sub>1</sub>: 270 Ω
- R<sub>2</sub>: 2.2 kΩ
- R<sub>3</sub>: 4.7 kΩ
- R<sub>4</sub>: 4.7 kΩ

Fig. 4 - 890-MHz common-base test circuit for gain and noise figure.



- C<sub>1</sub>: 1.0–30 pF
  - C<sub>2</sub>, C<sub>3</sub>: 1.0–20 pF
  - C<sub>4</sub>, C<sub>5</sub>: 0.04 μF
  - C<sub>6</sub>: 1–10 pF
  - L<sub>1</sub>: 2 turns No. 18 wire, 3/16 in. (0.188 mm) ID, 0.10 in. (2.54 mm) long
  - L<sub>2</sub>: 3 turns No. 18 wire, 3/16 in. (0.188 mm) ID, 0.15 in. (3.81 mm) long
  - L<sub>3</sub>-L<sub>4</sub>: 0.22-μH rf choke
  - L<sub>5</sub>: 3 turns No. 18 wire, 3/16 in. (0.188 mm) ID, 0.15 in. (3.81 mm) long
  - R<sub>1</sub>: 200Ω, 1/4 W
- \* V<sub>(BB)</sub> adjusted for I<sub>C</sub> = 1.5 mA

Fig. 5—Circuit diagram of 450-MHz amplifier used for measurement of noise figure.

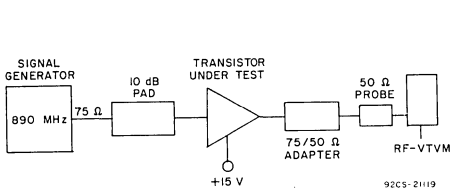


Fig. 6—Block diagram of test setup for measurement of gain.

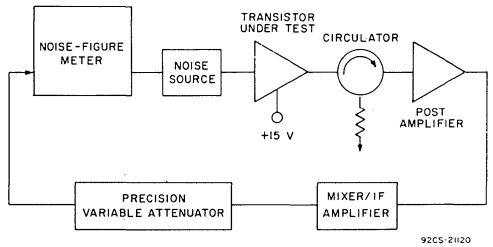


Fig. 7—Block diagram of noise-figure test set.

**TERMINAL CONNECTIONS**

- Lead 1 – Emitter
- Lead 2 – Base
- Lead 3 – Collector
- Lead 4 – Connected to case